

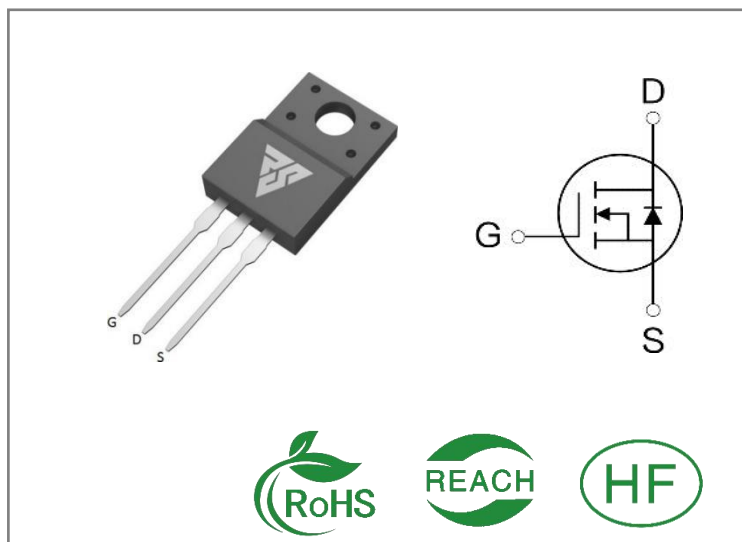
ID	$R_{DS(ON)}$ (Typ)	VDSS
11A	320mΩ	700V

Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- AC-DC Switching Power Supply

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability


Ordering Information

Part Number	Package	Marking	Packing	Qty.
RS70R380F	T0-220F	RS70R380F	Tube	50 PCS

Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	RS70R380F	Units
VDSS	Drain-to-Source Voltage	700	V
ID	Continuous Drain Current $T_C=25^\circ\text{C}$	11	A
ID	Continuous Drain Current $T_C=100^\circ\text{C}$	7	
IDM	Pulsed Drain Current (Note*1)	33	
Ptot	Total Power Dissipation	88	W
VGS	Gate- to- Source Voltage	± 30	V
EAS	Single Pulse Avalanche Energy $L=10\text{mH}, V_{DS}=50\text{V}, R_G=25\Omega, T_C=25^\circ\text{C}$	210	mJ
dv/dt	MOSFET dv/ dt ruggedness $V_{DS}=0\ldots 400\text{V}$	50	V/ns
dv/dt	Reverse diode dv/dt $V_{DS}=0\ldots 400\text{V}, T_j=25^\circ\text{C}, I_{SD}\leq I_D$	15	V/ns
TL TPKG	Maximum Temperature for Soldering	300 260	$^\circ\text{C}$
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds		
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the“ Absolute Maximum Ratings” Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS70R380F	Units	Test Conditions
R θ JC	Junction-to-Case	4	°C / W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 150 °C
R θ JA	Junction-to- Ambient	80		1 cubic foot chamber, free air.

OFF Characteristics TJ= 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	700	--	--	V	VGS=0V, ID=250μA
IDSS	Drain- to- Source Leakage Current	--	--	1	μA	VDS=700V, VGS=0V
IGSS	Gate- to- Source Forward Leakage	--	--	100	nA	VGS=30V, VDS=0V
	Gate- to- Source Reverse Leakage	--	--	-100		VGS=-30V, VDS=0V

ON Characteristics TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On-Resistance(Note*2)	--	320	360	mΩ	VGS=10V, ID=3.2A
VGS(TH)	Gate Threshold Voltage	2	--	4	V	VGS=VDS, ID=250μA

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time	--	18	--	nS	VDS=350V ID=11A RG=25Ω
trise	Rise Time	--	33	--		
td(OFF)	Turn- OFF Delay Time	--	68	--		
tfall	Fall Time	--	29	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	747	--	pF	VGS=0V VDS=50V f=400KHz
Coss	Output Capacitance	--	55	--		
Crss	Reverse Transfer Capacitance	--	3.3	--		
Qg	Total Gate Charge	--	20	--	nC	VDS=560V ID=11A VGS=10V
Qgs	Gate- to- Source Charge	--	3.7	--		
Qgd	Gate-to-Drain(" Miller") Charge	--	9	--		

Source- Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	11	A	Integral pn- diode in MOSFET
ISM	Maximum Pulsed Current	--	--	33	A	
VSD	Diode Forward Voltage	--	1.4	--	V	IS=11A,VGS=0V
trr	Reverse Recovery Time	--	326	--	nS	VR=100V IS=11A,di/dt=100A /μs
Qrr	Reverse Recovery Charge	--	2.9	--	μC	

Notes:

- * 1. Repetitive rating, pulse width limited by maximum junction temperature.
- * 2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%

Typical Feature Curve

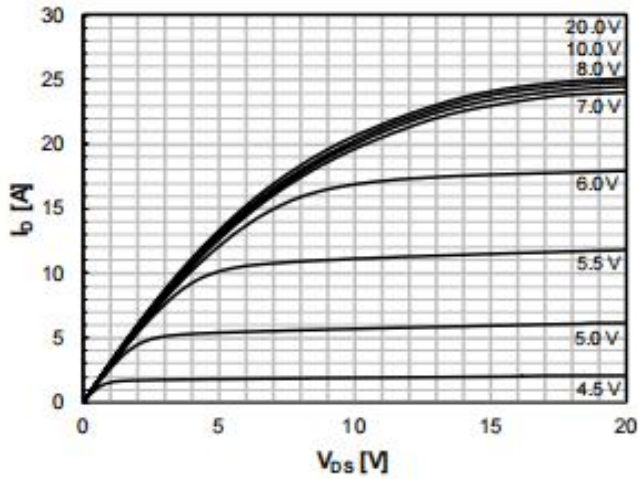


Fig. 1 Output characteristics

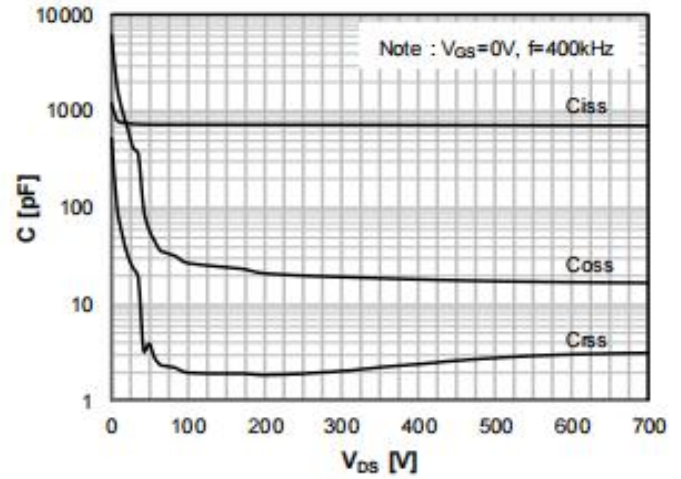


Fig. 2 Capacitances

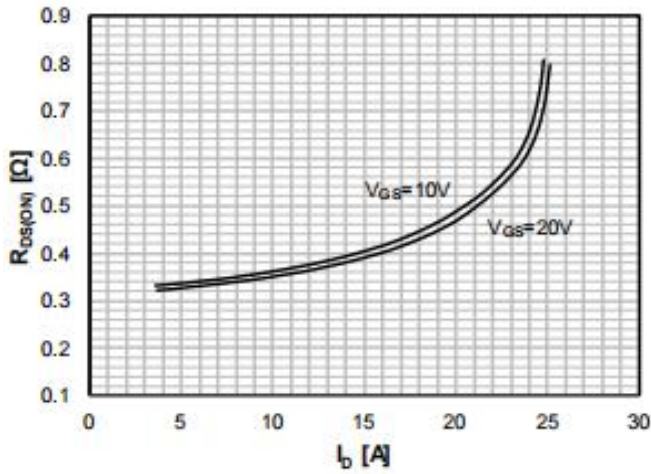


Fig. 3 On-state resistance

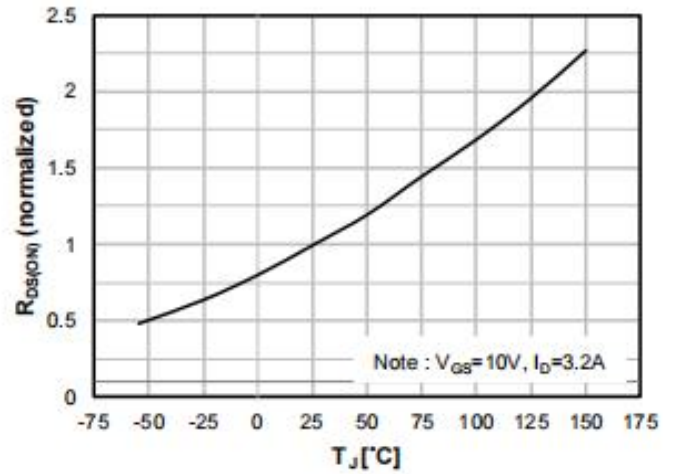


Fig. 4 On-state resistance with temperature

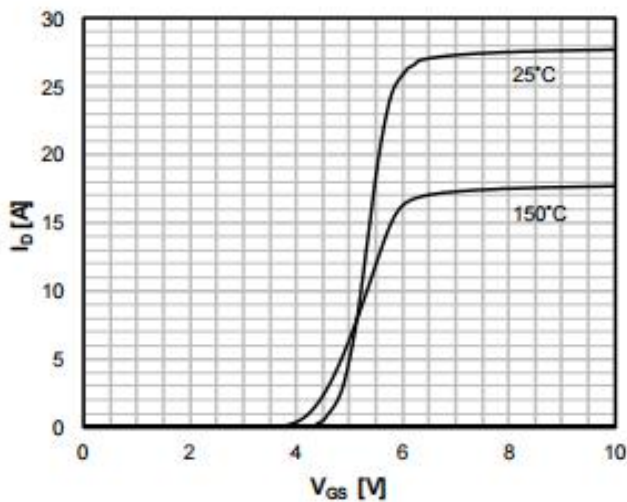


Fig 5. Transfer characteristics

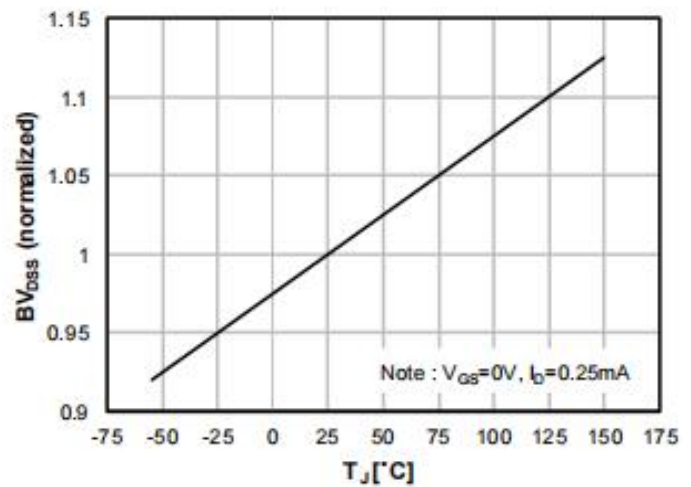
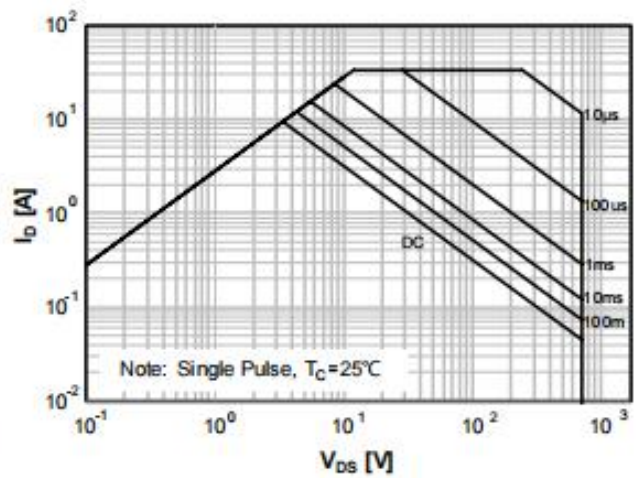
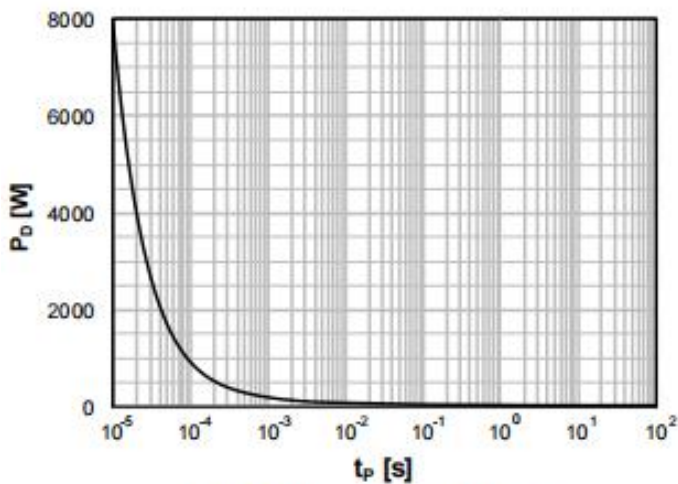
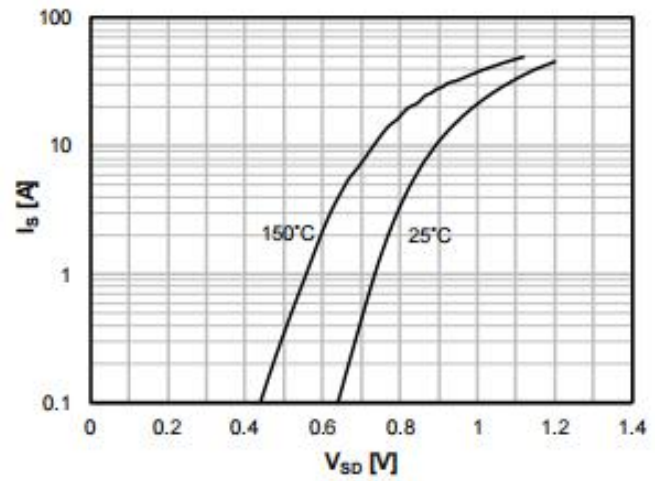
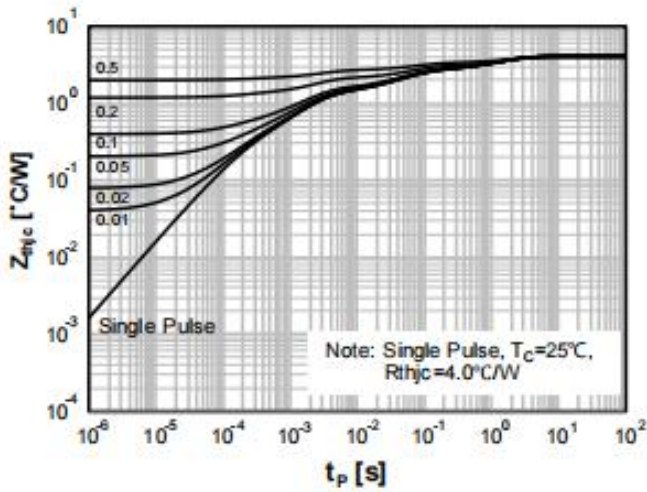
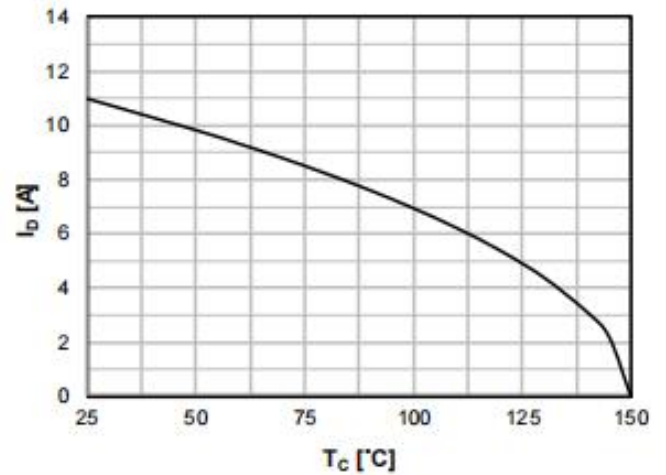
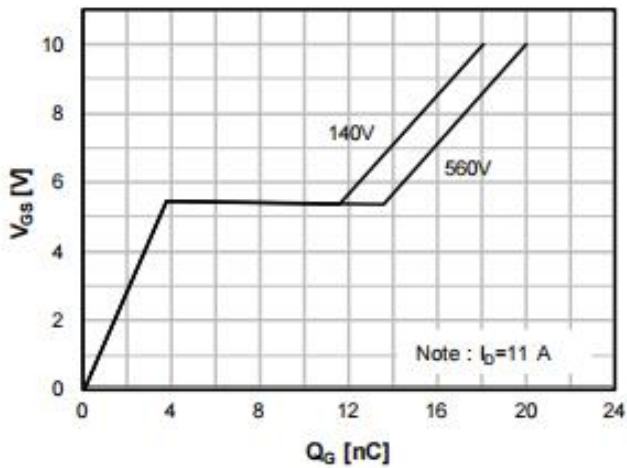


Fig 6. Breakdown voltage with temperature



Test Circuits and Waveforms

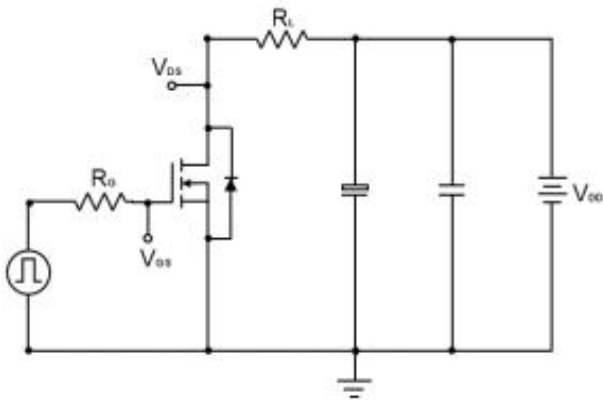


Fig 13. Test circuit for resistive load switching times

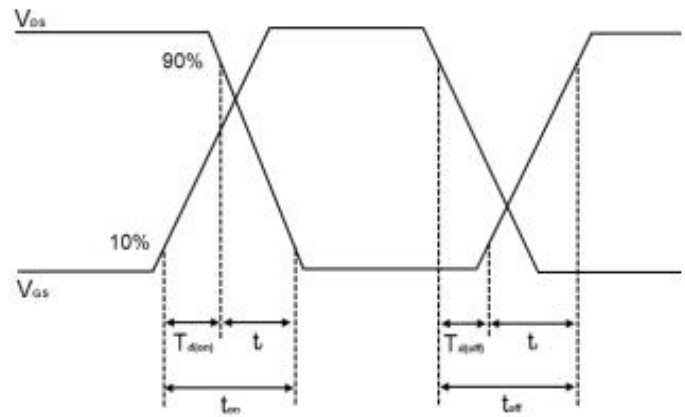


Fig 14. Switching times waveform

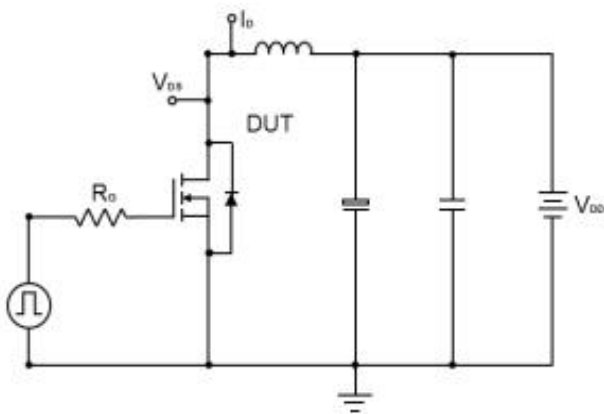


Fig 15. Test circuit for unclamped inductive load

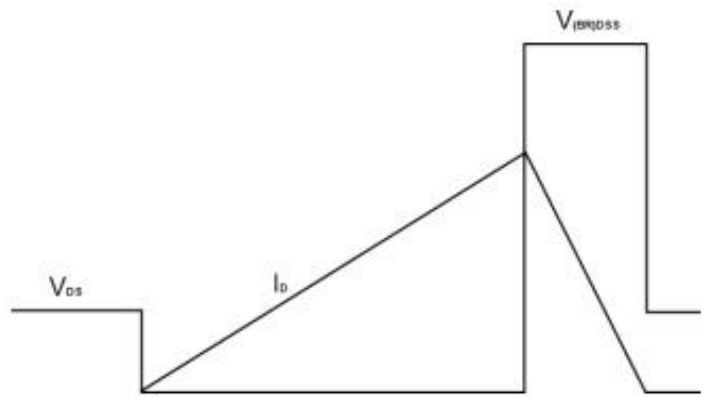


Fig 16. Unclamped inductive waveform

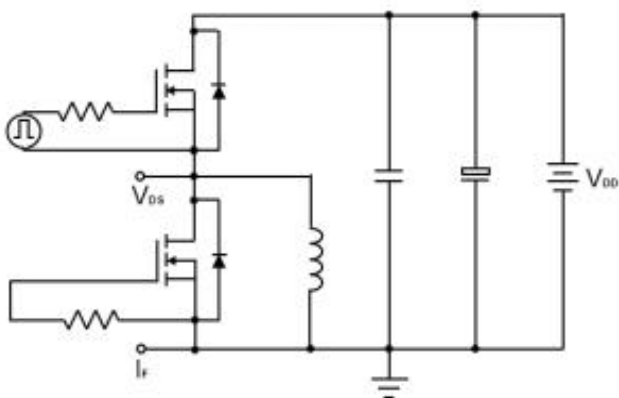


Fig 17. Test circuit for diode

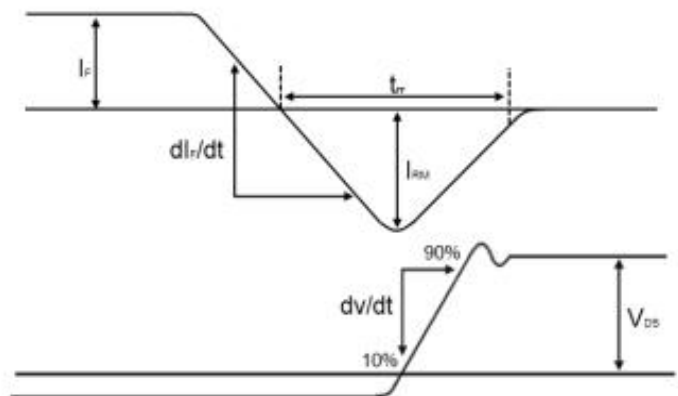
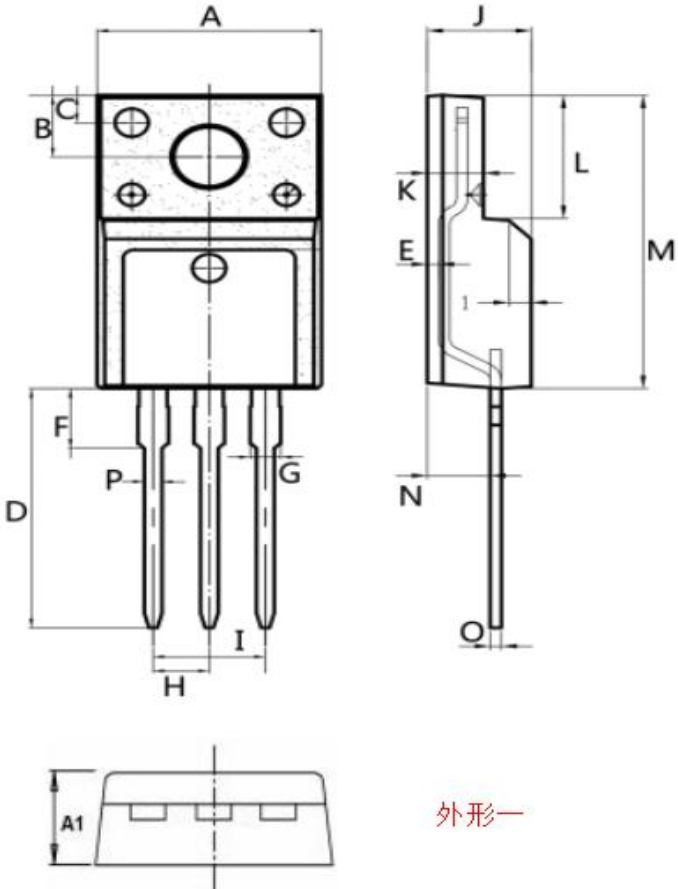
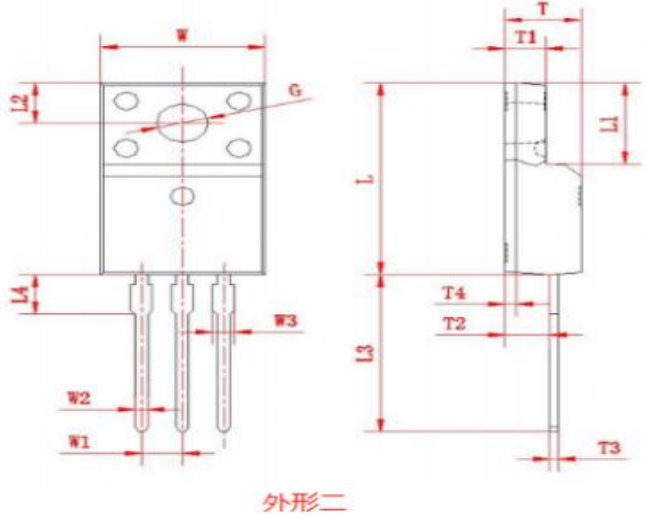


Fig 18. Diode recovery

Package outline drawing(TO-220F Unit: mm)

 <p>外形一</p>	Dim.	Min.	Max.
	A	9.95	10.36
	A1	4.5	5.0
	B	2.95	3.25
	C	1.25	1.45
	D	12.60	13.60
	E	0.40	0.60
	F	2.8	3.5
	G	1.30	1.45
	H	(2.54)	
	I	(5.08)	
	J	4.60	4.75
	K	2.45	2.65
	L	6.5	6.8
	M	15.4	16.0
	N	2.25	3.05
	O	0.45	0.55
	P	0.70	0.90
All Dimensions in millimeter			
 <p>外形二</p>	Dim.	Min.	Max.
	W	9.95	10.36
	W1	(2.54)	
	W2	0.70	0.90
	W3	1.25	1.47
	L	15.67	16.07
	L1	6.48	6.88
	L2	3.2	3.4
	L3	12.6	13.6
	L4	(3.23)	
	T	4.50	4.90
	T1	2.34	2.74
	T2	2.25	2.95
	T3	0.45	0.60
	T4	(0.70)	
	G	3.08	3.28
All Dimensions in millimeter			

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